## **Thomas Basler**

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/11436624/publications.pdf

Version: 2024-02-01

3311381 3475538 6 43 1 1 citations h-index g-index papers 7 7 7 39 docs citations citing authors times ranked all docs

#	Article	lF	CITATIONS
1	Impact of Degradation Mechanisms in Gate Stress Tests on the Hard-Switching Behavior of 1.2 kV SiC Power MOSFETs. , 2022, , .		O
2	Gate Oxide Reliability of 1.2 kV and 6.5 kV SiC MOSFETs under Stair-Shaped Increase of Positive and Negative Gate Bias. , 2021, , .		3
3	Switching ruggedness and surgeâ€current capability of diodes using the selfâ€adjusting p emitter efficiency diode concept. IET Circuits, Devices and Systems, 2014, 8, 205-212.	1.4	5
4	Dynamic self-clamping at short-circuit turn-off of high-voltage IGBTs. , 2013, , .		18
5	Measurement of a complete HV IGBT I-V-characteristic up to the breakdown point. , 2013, , .		7
6	Surge current capability of IGBTs. , 2012, , .		9